

NOTICE OF REVISION (NOR)		1. DATE (YYMMDD) 93-12-16		Form Approved OMB No. 0704-0188	
THIS REVISION DESCRIBED BELOW HAS BEEN AUTHORIZED FOR THE DOCUMENT LISTED.					
Public reporting burden for this collection is estimated to average 2 hours per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503. PLEASE DO NOT RETURN YOUR COMPLETED FORM TO EITHER OF THESE ADDRESSED. RETURN COMPLETED FORM TO THE GOVERNMENT ISSUING CONTRACTING OFFICER FOR THE CONTRACT/PROCURING ACTIVITY NUMBER LISTED IN ITEM 2 OF THIS FORM.				2. PROCURING ACTIVITY NO.	
				3. DODAAC	
4. ORIGINATOR		b. ADDRESS (Street, City, State, Zip Code) Defense Electronics Supply Center 1507 Wilmington Pike Dayton, OH 45444-5270		5. CAGE CODE 67268	
a. TYPED NAME (First, Middle Initial, Last)				6. NOR NO. 5962-R066-94	
				7. CAGE CODE 67268	
				8. DOCUMENT NO. 5962-88744	
9. TITLE OF DOCUMENT Microcircuit, Linear, Dual Differential Line Driver, Monolithic Silicon.			10. REVISION LETTER		11. ECP NO. No registered users
12. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES					
13. DESCRIPTION OF REVISION					
<p>Sheet 1: Revisions ltr column; add "B". Revisions description column; add "Changes in accordance with NOR 5962-R066-94". Revisions date column; add "93-12-16". Revision level block; add "B". Rev status of sheets; For sheets 1, 2, and 7 add "B".</p> <p>Sheet 2: 1.2.2 Case Outline(s); Add: Outline letter "F", Descriptive designator "GDFP2-F16 or CDFP3-F16", Terminals "16", and Package style "Flat pack". 1.3 Absolute Maximum Ratings; Delete: "Thermal resistance, junction-to-ambient (θ_{JA}) - - - - 65°C/W" Add: "Thermal resistance, junction-to-ambient (θ_{JA}): Case outline 2 - - - - - 65°C/W Case outline F - - - - - 124°C/W" Revision level block; add "B".</p> <p>Sheet 7: See sheet 2.</p>					
14. THIS SECTION FOR GOVERNMENT USE ONLY					
a. (X one)	X	(1) Existing document supplemented by the NOR may be used in manufacture.			
		(2) Revised document must be received before manufacturer may incorporate this change.			
		(3) Custodian of master document shall make above revision and furnish revised document.			
b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT			c. TYPED NAME (First, Middle Initial, Last)		
DESC			MICHAEL A. FRYE		
d. TITLE		e. SIGNATURE		f. DATE SIGNED	
MICROELECTRONICS BRANCH CHIEF		MICHAEL A. FRYE		(YYMMDD) 93-12-16	
15a. ACTIVITY ACCOMPLISHING REVISION		b. REVISION COMPLETED (Signature)		c. DATE SIGNED	
DESC		SANDRA B. ROONEY		(YYMMDD) 93-12-16	

Sheet 7: (Continued).

Delected terminal connections figure and replace with the following:

Device type	01		02	
Case outline	F	2	F	2
Terminal number	Terminal symbol			
1	1ZP	NC	1ZP	NC
2	1ZS	1ZP	1ZS	1ZP
3	1YS	1ZS	1YS	1ZS
4	1YP	1YS	1YP	1YS
5	1A	1YP	1A	1YP
6	1B	NC	1B	NC
7	1C	1A	1C	1A
8	GND	1B	GND	1B
9	CC	1C	CC	1C
10	2C	GND	2C	GND
11	2A	NC	2A	NC
12	2YP	CC	2YP	CC
13	2YS	2C	2YS	2C
14	2ZS	2A	2ZS	2A
15	2ZP	2YD	2ZP	2YD
16	V _{CC}	NC	V _{CC}	NC
17	---	2YS	---	2YS
18	---	2ZS	---	2ZS
19	---	2ZP	---	2ZP
20	---	V _{CC}	---	V _{CC}

Revision level block; add "B".

REVISIONS																			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																
A	Add device types 02. Editorial changes throughout.	92 - 09 - 24	Michael A. Frye																

REV																			
SHEET																			
REV																			
SHEET																			
REV STATUS OF SHEETS				REV		A	A	A	A	A	A	A	A	A	A	A	A		
				SHEET		1	2	3	4	5	6	7	8	9	10	11	12		
PMIC N/A				PREPARED BY JOSEPH A. KERBY						DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444									
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A				CHECKED BY CHARLES E. BESORE															
				APPROVED BY MICHAEL A. FRYE															
				DRAWING APPROVAL DATE 91-02-07															
								REVISION LEVEL A						SIZE A		CAGE CODE 67268		5962-88744	
SHEET 1 OF 12																			

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

[illegible]

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	55113	Dual differential line driver with three state outputs
02	55114	Dual differential line driver with two state outputs

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
2	CQCC1	20	Square leadless chip carrier

1.3 Absolute maximum ratings

Supply voltage (V_{CC}) 1/	+7.0 V dc
Input voltage	+5.5 V dc
Off-state output voltage	+12.0 V dc
Maximum power dissipation (P_D)	1000 mW
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+260°C
Thermal resistance, junction-to-case (θ_{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ_{JA})	65°C/W
Junction temperature (T_J)	+150°C

Supply voltage (V_{CC})	+4.5 V dc to +5.5 V dc
Ambient operating temperature range (T_A)	-55°C to +125°C
Minimum high level input voltage (V_{IH})	2.0 V dc
Maximum low level input voltage (V_{IL})	0.8 V dc
Maximum low level output current (I_{OL})	40 mA
High level output current (I_{OH})	-40 mA

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2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and bulletin. Unless otherwise specified, the following specification, standards, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARDS

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

MIL-STD-1835 - Microcircuit Case Outlines.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standards, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections and truth tables. The terminal connections and truth tables shall be as specified on figure 1.

3.2.2 Waveforms and test circuits for low-to-high and high-to-low outputs. The waveforms and test circuits for low-to-high and high-to-low outputs shall be as specified on figure 2.

3.2.3 Waveforms and test circuit for enable-to-high and high-to-disable. The waveforms and test circuit for enable-to-high and high-to-disable outputs shall be as specified on figure 3.

3.2.4 Waveforms and test circuit for enable-to-low and low-to-disable outputs. The waveforms and test circuit for enable-to-low and low-to-disable outputs shall be as specified on figure 4.

3.2.5 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

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TABLE I. Electrical performance characteristics.

Test		Symbol	Conditions 1/ -55° C ≤ T _C ≤ +125° C unless otherwise specified		Device types	Group A Subgroups	Limits		Unit
							Min	Max	
Low level output voltage		V _{OL}	V _{CC} = 4.5 V, I _{OL} = 40 mA		All	1, 2, 3		0.4	V
High level output voltage		V _{OH}	V _{CC} = 4.5 V V _{IH} = 2 V V _{IL} = 0.8 V	I _{OH} = -10 mA	All	1, 2, 3	2.4		V
				I _{OH} = -40 mA			2.0		
Input clamp voltage		V _{IK}	V _{CC} = 4.5 V, I _{IN} = -12 mA		All	1, 2, 3		-1.5	
Low level input current	A,B ,C	I _{IL}	V _{CC} = 5.5 V, V _{IN} = 0.4 V		All	1, 2, 3		-1.6	mA
	CC				01			-3.2	
High level input current	A,B ,C	I _{IH}	V _{CC} = 5.5 V, V _{IN} = 2.4 V		All	1, 2, 3		40	uA
	CC				01	1		80	
Output clamp voltage		V _{OK}	V _{CC} = 5.5 V, I _O = -40 mA		02	1		-1.5	V
			V _{CC} = 5.0 V, I _O = +40 mA					6.5	
Supply current		I _{CC}	All inputs at 0 V, No load	V _{CC} = 5.5 V	01	1, 2, 3		65	mA
				V _{CC} = 7.0 V				85	
				V _{CC} = 5.5 V	02	1, 2, 3		50	
				V _{CC} = 7.0 V				65	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ $-55^{\circ}\text{C} \leq T_C \leq +125^{\circ}\text{C}$ unless otherwise specified		Device types	Group A Subgroups	Limits		Unit
						Min	Max	
Off-state (high impedance) output current	I_{OZ}	$V_{CC} = 5.5\text{ V}$ Output controls at 0.8 V	$V_O = 0\text{ V to } V_{CC}$	01	1		± 10	μA
			$V_O = 0\text{ V}$		2		-150	
			$V_{CC} = 0.4\text{ V}$		2		± 80	
			$V_{CC} = 2.4\text{ V}$		2		± 80	
			$V_{CC} = V_{CC}$		2		80	
Off-state (open-collector) output current	$I_{O(OFF)}$	$V_{CC} = 5.5\text{ V}$ $V_{OH} = 12\text{ V}$		A01	1	2.4	10	μA
				02		2.0	100	
				All	2		200	
Input current at maximum input voltage	I_I	$V_{CC} = 5.5\text{ V}$	A, B, C	All	1, 2, 3		1	mA
			C C	01			2	
Short circuit output current	I_{OS}	$V_{CC} = 5.5\text{ V}$, $V_{OUT} = 0\text{ V}$ $T_A = 25^{\circ}\text{C}$		All	1	-40	-120	
Functional test		See 4.3.1.c		All	7, 8			
Propagation delay time	t_{PLH} t_{PHL}	$T_A = +25^{\circ}\text{C}$, $V_{CC} = 5\text{ V}$, $C_L = 30\text{ pF}$, See figure 2		All	9		20	ns
							20	
Output enable time to high level	t_{PZH}	$R_L = 180\Omega$, $T_A = +25^{\circ}\text{C}$, $V_{CC} = 5\text{ V}$, $C_L = 30\text{ pF}$, See figure 3		01	9		15	
Output enable time to low level	t_{PZL}	$R_L = 180\Omega$, $T_A = +25^{\circ}\text{C}$, $V_{CC} = 5\text{ V}$, $C_L = 30\text{ pF}$, See figure 4		01	9		30	
Output disable time from high level	t_{PHZ}	$R_L = 180\Omega$, $T_A = +25^{\circ}\text{C}$, $V_{CC} = 5\text{ V}$, $C_L = 30\text{ pF}$, See figure 3		01	9		20	
Output disable time from low level	t_{PLZ}	$R_L = 250\Omega$, $T_A = +25^{\circ}\text{C}$, $V_{CC} = 5\text{ V}$, $C_L = 30\text{ pF}$, See figure 4		01	9		35	

1/ All parameters, with the exception of off-state open collector output current ($I_{O(OFF)}$), are measured with the active pull-up connected to the sink output.

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3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-EC shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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Device type	01	02
Case outline	2	
Terminal number	Terminal symbol	
1	NC	NC
2	1ZP	1ZP
3	1ZS	1ZS
4	1YS	1YS
5	1YP	1YP
6	NC	NC
7	1A	1A
8	1B	1B
9	1C	1C
10	GND	GND
11	NC	NC
12	CC	2A
13	2C	2B
14	2A	2C
15	2YP	2YP
16	NC	NC
17	2YS	2YS
18	2ZS	2ZS
19	2ZP	2ZP
20	V _{CC}	V _{CC}

Device type 01

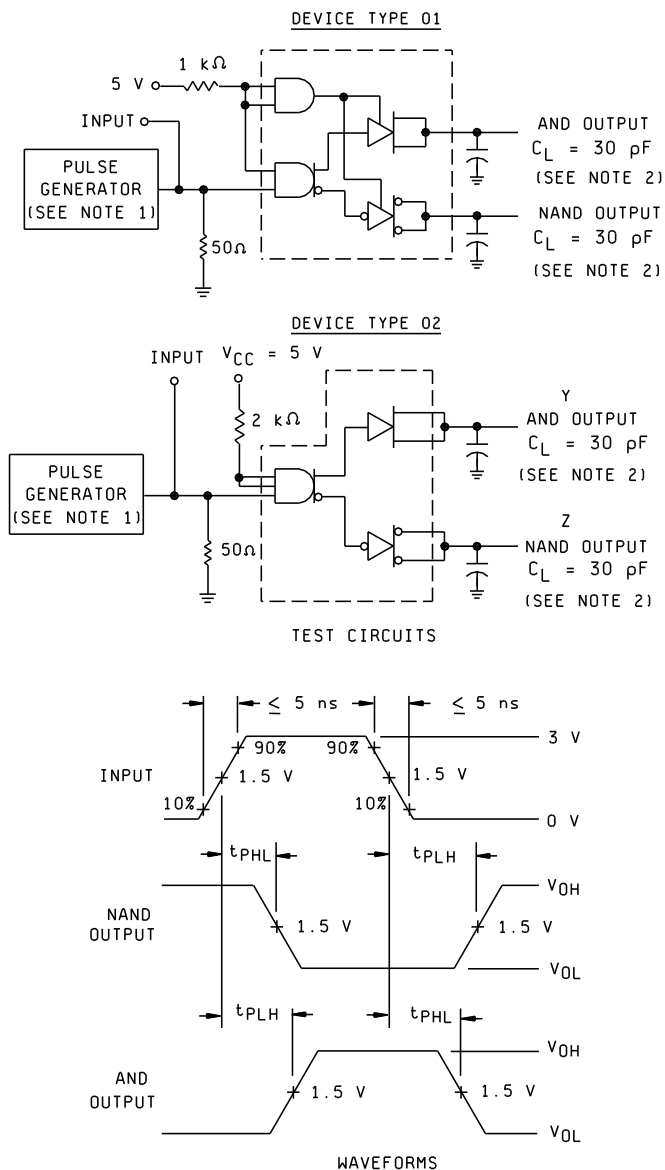
Inputs				Output			
1A or 2A	1B	1C or 2C	CC	ZP	ZS	YS	YP
L	L or H	H	H	H	Hi Z	L	Hi Z
L or H	L	H	H	H	Hi Z	L	Hi Z
H	H	H	H	Hi Z	L	Hi Z	H
L or H	L or H	L	L or H	Hi Z	Hi Z	Hi Z	Hi Z
L or H	L or H	L or H	L	Hi Z	Hi Z	Hi Z	Hi Z

Device type 01

Inputs			Outputs	
A	B	C	Y	Z
H	H	H	H	L
All other input combinations			L	H

FIGURE 1. Terminal connections and truth table.

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NOTES:

1. The pulse generator has the following characteristics $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$, $t_W = 100 \text{ ns}$.
2. C_L includes probe and jig capacitance.

FIGURE 2. Waveforms and test circuit for low-to-high and high-to-low outputs.

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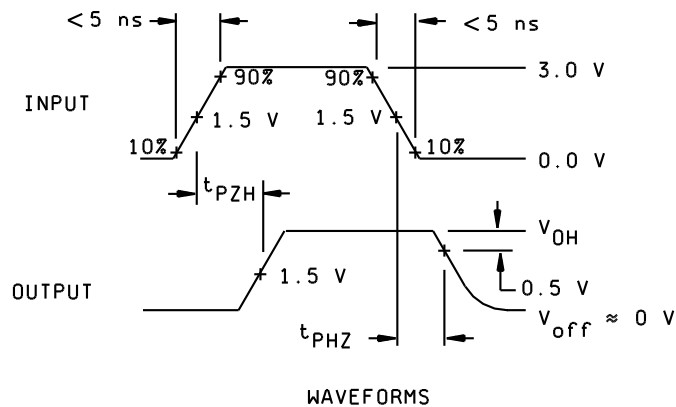
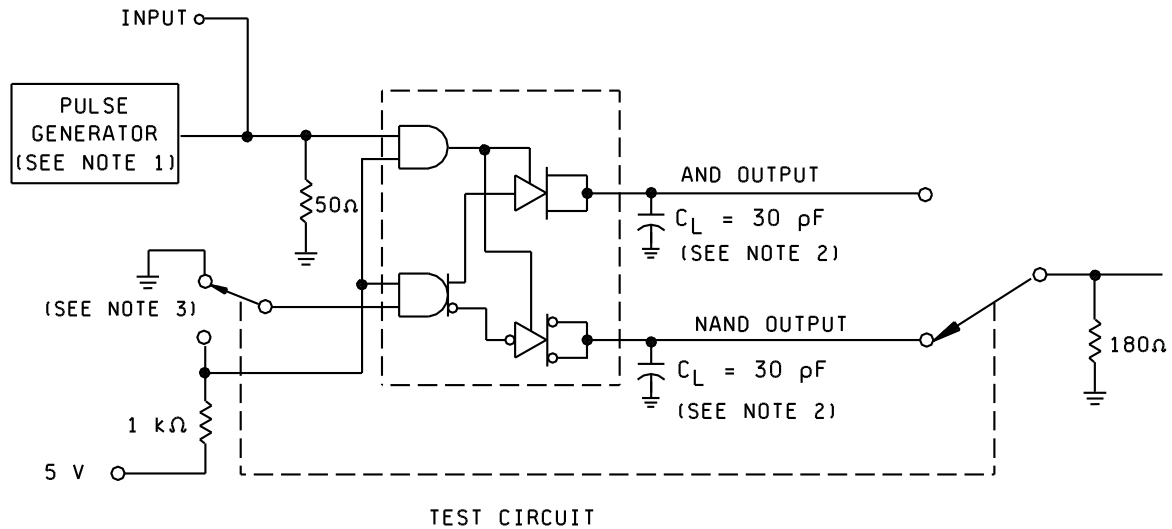
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DEVICE TYPE 01



NOTES:

1. The pulse generator has the following characteristics $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$, $t_W = 100 \text{ ns}$.
2. C_L includes probe and jig capacitance.
3. The parameter from table I is valid with the switch in either position.

FIGURE 3. Waveforms and test circuit for enable-to-high and high-to-disable.

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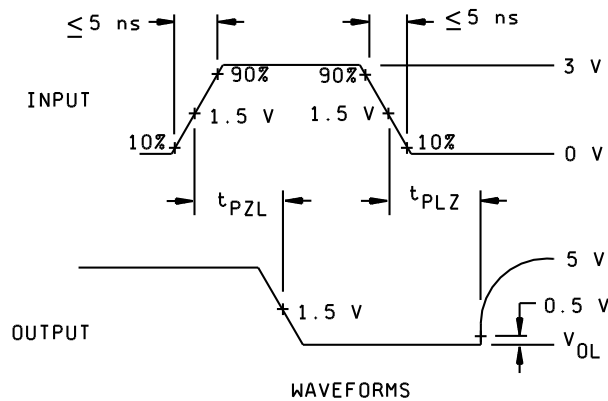
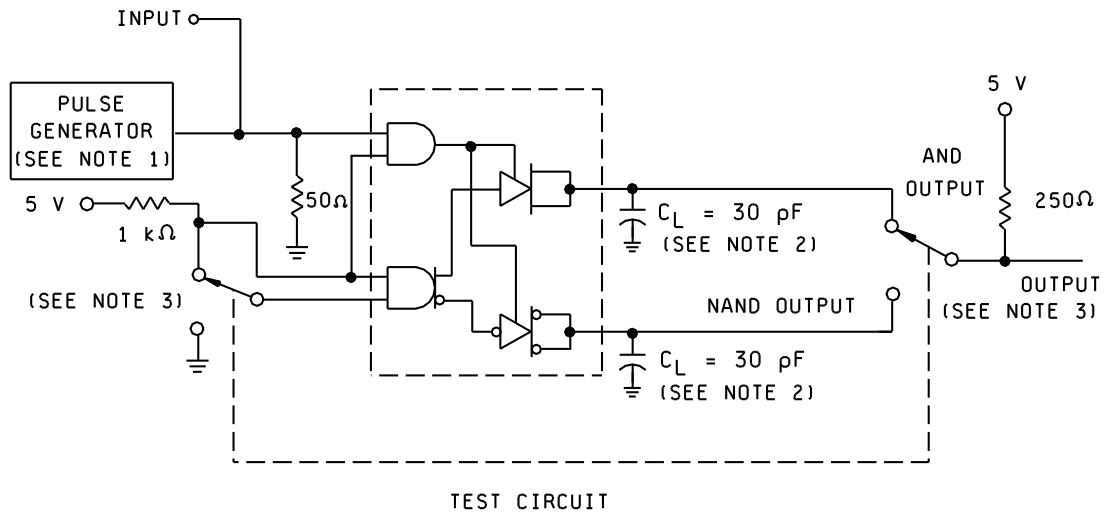
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DEVICE TYPE 01



NOTES:

1. The pulse generator has the following characteristics $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$, $t_W = 100 \text{ ns}$.
2. C_L includes probe and jig capacitance.
3. The parameter from table I is valid with the switch in either position.

FIGURE 4. Waveforms and test circuit for enable-to-low and low-to-disable outputs.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, 10, and 11 in table 1, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroups 7 and 8 shall be sufficient to verify the truth table.

4.3.2. Group C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883:

(1) Test condition A, B, C, or D. the test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) $T_A = +125^\circ\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per mehtod 5005, table 1)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9
Group C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroups 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.

6.5 Comments. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444, or telephone (513) 296-5377.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-EC.

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STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 92-09-24

Approved sources of supply for SMD 5962-88744 are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-EC. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN <u>1/</u>
5962-88744012X	01295	SNJ55113FK
5962-88744022X		SNJ55114FK

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

Vendor name
and address

01295

Texas Instruments, Incorporated
13500 N Central Expressway
P.O. Box 655303
Dallas, TX 75265
Point of contact: I-20 at FM 1788
Midland, TX 79711-0448

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